November 1, 2007, 7:45-8:45 p.m., Education Building Auditorium EDU 305

David J. Dwyer presents "Software Reliability Methods and Experience"

David J. Dwyer is a reliability engineer at BAE Systems, Nashua, NH. He has a M.S. in Computer Science from Rivier College (1999), M.S. in Electrical Engineering from Northeastern University (1980), and B.S. in Physics from Providence College (1963).

The presentation addresses methodology in estimating and projecting software reliability. It will help academic audience to find answers to vital questions: How reliable are industrial software products? Can software reliability be measured exactly? New methods are offered for estimating the test time required and software failures to be corrected to reach reliability goals of the test-and-fix programs.